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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re Appln of: Melvin K. CARTER et al.

Confirmation No: 5933

Serial No: 10/690,623

Group: 1765

Filed: October 23, 2003

Examiner: Lan Vihn

Entitled: **CMP METHOD FOR COPPER,
TUNGSTEN, TITANIUM,
POLYSILICON, AND OTHER
SUBSTRATES USING ORGANOSULFONIC
ACIDS AS OXIDIZERS**

Atty Docket: 063254-0202

INFORMATION DISCLOSURE STATEMENT

U.S. Patent and Trademark Office
Randolph Building- **MAIL STOP-AMENDMENT**
401 Dulany Street
Alexandria, Virginia 22314

Sir:


Pursuant to applicants' duty of disclosure under 37 C.F.R. 1.56, attached is a PTO-1449 citing nineteen (19) references which are believed of interest. One (1) copy of the Japanese reference is enclosed; the remaining references are all U.S.

It is requested that the Examiner make this information of record if it is deemed material to the examination of the application by initialing and returning the attached PTO-1449.

A fee of **\$180.00** is believed due, however, should it be deemed additional fees or credits are due in this matter, the Examiner is authorized to charge/credit Morgan, Lewis & Bockius LLP Deposit Account No. 50-0310.

Respectfully submitted,

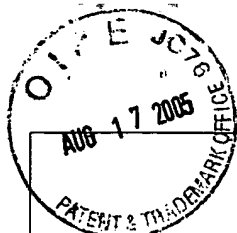
Date August 17, 2005


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08/19/2005 EFLORES 00000137 500310 10690623

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LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

ATTY DOCKET NO.

063254-0202-US

APPLICATION NO

10/690,623

APPLICANT

Melvin K. CARTER et al.

FILING DATE

October 23, 2003

GROUP

1765

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	A01	6,117,784	09/2000	Uzoh			
	A02	6,527,622	03/2003	Brusic et al.			
	A03	6,740,589	05/2004	Shimazu et al.			
	A04	6,750,128	06/2004	Kondo et al.			
	A05	6,786,944	09/2004	Hattori et al.			
	A06	6,852,632	02/2005	Wang et al.			
	A07	2003/0181142	09/2003	De Rege Thesauro et al.			
	A08	2003/0196386	10/2003	Hattori et al.			
	A09	2003/0203624	10/2003	Sameshima et al.			
	A10	2004/0014413	01/2004	Kawahashi et al.			
	A11	2004/0063391	04/2004	Hosaka et al.			
	A12	2004/0132305	07/2004	Nishimoto et al.			
	A13	2004/0162011	08/2004	Konno et al.			
	A14	2004/0166779	08/2004	Balijepalli et al.			
	A15	2004/0173574	09/2004	Grunwald			
	A16	2004/0235407	11/2004	Grunwald			
	A17	2004/0266326	2/2004	Shiho et al.			
	A18	2005/0026444	02/2005	Babu et al.			
	A19						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	B01	2002 087398	03/2002	Japan				
	B02							
	B03							

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.